

Notice of References Cited	Application/Control No. 10/574,227	Applicant(s)/Patent Under Reexamination HEINIS, CHRISTIAN	
	Examiner Anand U. Desai, Ph.D.	Art Unit 1656	Page 1 of 1

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	L	US-			
	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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